



APPROVED METHOD:
MEASURING LUMINOUS FLUX
WAVEFORMS FOR USE IN TEMPORAL
LIGHT ARTIFACT (TLA) CALCULATIONS
AN AMERICAN NATIONAL STANDARD

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ANSI/IES LM-90-20

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has been approved by IES.
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**Prepared for IES
By the Testing Procedures Committee**



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CONTENTS

1.0	Introduction and Scope	1
1.1	Introduction	1
1.2	Scope	1
2.0	Normative References	1
2.1	CIE TN 006:2016	1
2.2	IES LM-9-09/R17	1
2.3	ANSI/IES LM-45-20	1
2.4	ANSI/IES LM-51-20	2
2.5	ANSI/IES LM-66-20	2
2.6	ANSI/IES LM-78-17	2
2.7	ANSI/IES LM-79-19	2
2.8	ANSI/IES LS-1-20	2
2.9	NEMA 77-2017	2
2.10	NEMA SSL 7A-2015	2
3.0	Ambient and Physical Test Conditions	2
3.1	Ambient Temperature	2
3.2	Air Movement	2
3.3	Vibration	3
3.4	Humidity	3
3.5	Stray Light	3
4.0	Test Equipment	3
4.1	Power Analyzer	4
4.2	Dimmer	4
4.2.1	Forward Phase-Cut Dimming	4
4.2.2	Application Specific Dimming	4
4.3	Test Chamber	4
4.3.1	Integrating Sphere	4
4.3.2	Optically Isolated Chamber or Dark Room	4
4.4	Oscilloscope or Digitizer	5
4.5	Transimpedance Amplifier	5
4.6	Low-Pass Filter	5
4.7	Photodetector	5
4.8	Voltage Differential Probe	5

5.0	Measurement Process	5
5.1	Setup	6
5.2	Input Power	6
5.2.1	Standard Input Power	6
5.2.2	Nonstandard Input Power	6
5.3	Input Voltage	6
5.4	Dimming	6
5.5	Stabilization	6
5.6	Measurement	7
5.6.1	Dark signal	7
6.0	Luminous Flux Waveform Data File	7
6.1	Version Element	8
6.2	Header Element	8
6.2.1	Manufacturer Element	8
6.2.2	Product Number Element	8
6.2.3	Description Element	8
6.2.4	Configuration	8
6.2.5	Laboratory Element	8
6.2.6	Report Number Element	8
6.2.7	Report Date Element	8
6.2.8	Comment Element	9
6.3	Equipment Element	9
6.3.1	Test Chamber Element	9
6.3.2	Measurement Equipment Element	9
6.3.3	Auxiliary Equipment Element	9
6.3.4	Setup Media Element	10
6.4	TLA Data Element	10
6.4.1	Nonstandard Conditions Element	11
6.4.2	Additional Information Element	11
6.4.3	Uncertainty Statement Element	11
6.4.4	Rated Electrical Input Element	11
6.4.5	Frequency Element	11
6.4.6	DUT Measurement Data Element	11
7.0	Uncertainty Analysis	15
	Informative Annex A – Descriptions of TLA Metrics	16
	Informative Annex B – XML Schema	19
	Informative Annex C – Sample TLA XML Document	22
	Informative Annex D – Uncertainty Example	24
	Informative References	25

1.0 Introduction and Scope

1.1 Introduction

Cyclic variations in luminous output from a light source or lighting system are known as temporal light modulation (TLM). TLM is known to affect visual perception, cognition, and brain activity. The variety of TLM patterns of solid-state lighting has brought these effects to the attention of the lighting community. Research seeks to create new metrics that predict the occurrence of visual, cognitive, and neurological effects based on measurements of the physical stimulus, the luminous flux waveform. This Lighting Measurement (LM) standard defines the method to reliably record, accurately measure, and reliably reproduce luminous flux waveforms and data sets from light sources for use in TLA calculations. **Informative Annex A** provides known calculation definitions typically utilized in TLA analysis.

1.2 Scope

This approved method describes the procedures to be followed and precautions to be observed in performing reproducible luminous flux waveform measurements for use in temporal light artifact (TLA) calculations under standard conditions. This document provides a description of the method of measurement, equipment requirements, and formulation of luminous flux waveforms for use in the calculations of temporal light artifacts from light sources. Luminous flux waveforms utilized in TLA calculations are for luminous flux frequencies between 1 Hz and 3,000 Hz under various control conditions. In addition, data reporting formats are described.

Intentionally flashing or signaling lights outside the defined frequency range are not included within the scope of this document.

2.0 Normative References

2.1 CIE TN 006:2016

International Commission on Illumination (CIE). CIE TN 006:2016, Visual Aspects of Time-Modulated Lighting Systems – Definitions and Measurement Models. Vienna: CIE; 2016.

2.2 ANSI/IES LM-9-20

Illuminating Engineering Society. Approved Method: Electrical and Photometric Measurement of Fluorescent Lamps. New York: IES; 2020.

For measurements of fluorescent lamps, the laboratory shall meet the requirements stated therein.

2.3 ANSI/IES LM-45-20

Illuminating Engineering Society. Approved Method: Electrical and Photometric Measurement of General Service Incandescent Filament Lamps. New York: IES; 2020.

For measurements of general service incandescent filament lamps, the laboratory shall meet the requirements stated therein.